Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/642,266	NAKANO ET AL.	
Examiner	Art Unit	
Vuthe Siek	2825	

SEARCHED				
Class	Subclass	Date	Examiner	
716	2,5,8- 11,19-21	3/30/2005	VS	
430	5,311,313	3/30/2005	vs	
438	57-60	3/30/2005	VS	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
EAST ALL DATABASES	3/30/2005	VS